We detect:

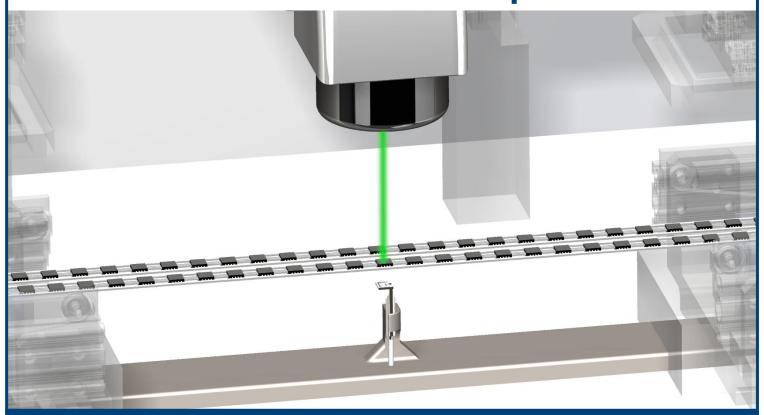
Cracks in multilayer ceramic capacitors (MLCC)

Delaminations in MEMS devices (e·g·, gas sensors)

Cracks in pad craters, glass substrates, and embedded devices

High-speed non-contact

Ultrasonic Inline Inspection





Ultra-fast single-shot mode

What makes it unique

XARION's laser-based technology enables the ultrasonic inspection of microelectronic components without any coupling liquid.

A single laser pulse generates an acoustic fingerprint of each sample, revealing **internal delaminations and defects** with a throughput of up to 1000 samples per second. The fully non-contact sensor technology can be easily integrated into a high-volume production line, saving costs for offline analysis and ensuring inspection of 100% of the components, e.g., packaged devices for the automotive sector.

Advantages

- 100% documented safety for your customer
- Unique non-contact single-shot ultrasound technology
- Fully automated inline inspection of up to 1000 samples per second
- Easy integration into high-throughput production environment:
 - No water coupling, and no drying of samples necessary
 - No interference with other production steps
- Combination with offline non-contact imaging of defective components

for further analysis possible

